



UNIVERSITY OF NEBRASKA-LINCOLN

Physics & Astronomy

Hall Effect and its Measurements

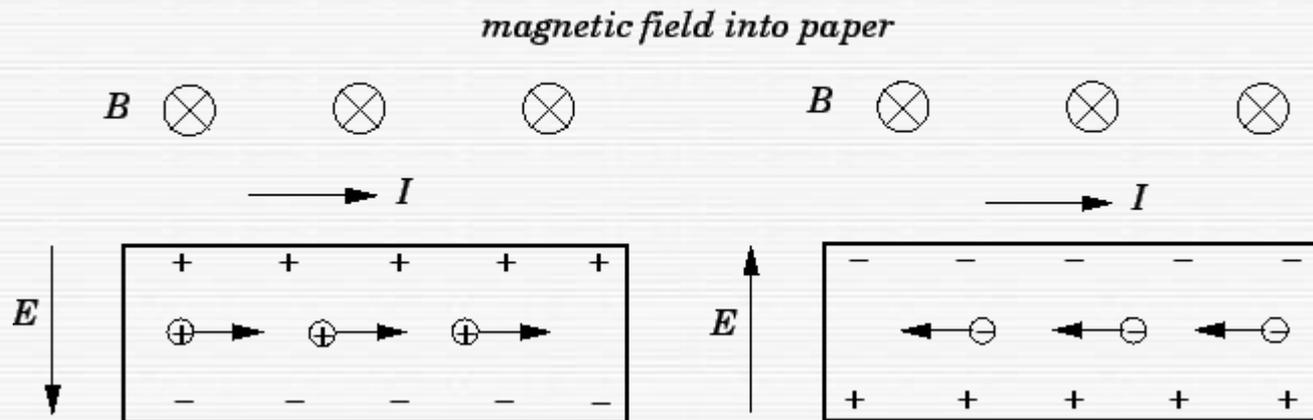
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11/13/2015



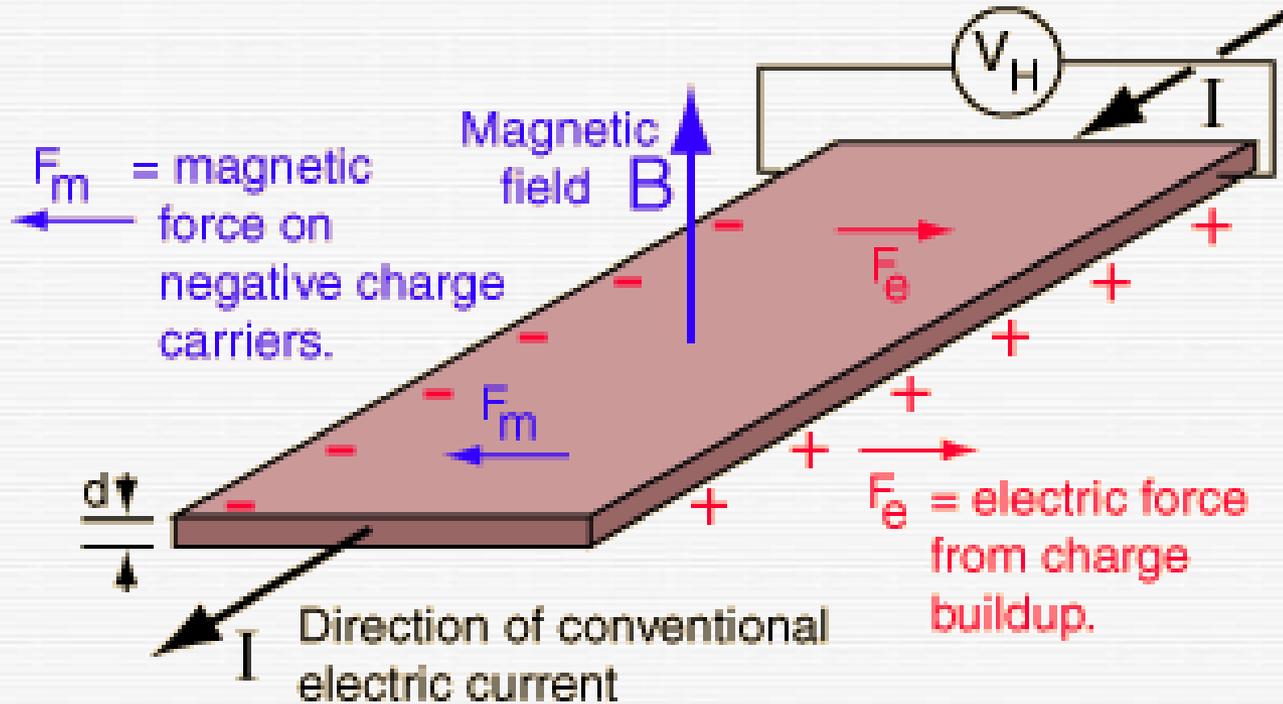
Hall effect

If an electric current flows through a conductor in a magnetic field, the magnetic field exerts a transverse force on the moving charge carriers which tends to push them to one side of the conductor.





Hall Voltage for Positive Charge Carriers



$$V_H = \frac{IB}{ned}$$

Charge Carriers in the Hall Effect



- The Hall effect is **different for different charge carriers**.
- In most common electrical applications, the conventional current is used partly because it makes no difference whether you consider positive or negative charge to be moving.
- The Hall voltage has a different polarity for positive and negative charge carriers, and it has been used to study the details of conduction in semiconductors and other materials which show **a combination of negative and positive charge carriers**.

Charge Carriers in the Hall Effect

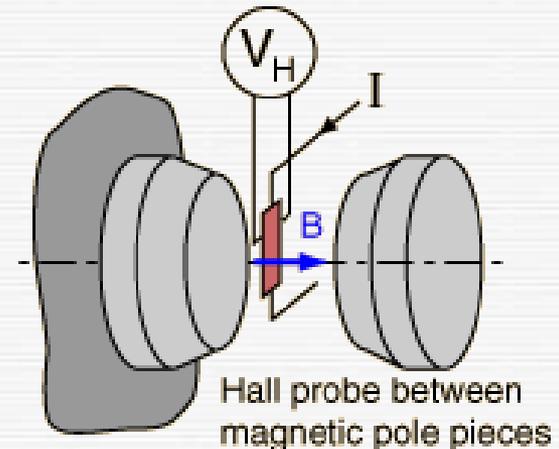


- The Hall effect can be used to measure the **average drift velocity** of the charge carriers
- Mechanically moving the Hall probe at different speeds until the Hall voltage disappears, showing that the charge carriers are now **not moving with respect to the magnetic field**.
- Other types of investigations of carrier behavior are studied in the quantum Hall effect.

Hall Probe

The measurement of **large magnetic fields on the order of a Tesla** is often done by making use of the Hall effect. A thin film Hall probe is placed in the magnetic field and the transverse voltage (on the order of microvolts) is measured.

Sometimes a thin copper film of thickness d on the order of 100 micrometers is used for a Hall probe.



The polarity of the Hall voltage for a copper probe shows that electrons are the charge carriers.



New Discoveries

- Quantum Hall Effect
- Spin Hall Effect
- Anomalous Hall Effect



Quantum Hall Effect

- Quantization of normal Hall Effect
- Seen at **low temperature, high magnetic field**
- Very precise, magnitude determined by Landau levels and electron interaction

$$\sigma = \nu \frac{e^2}{h}$$



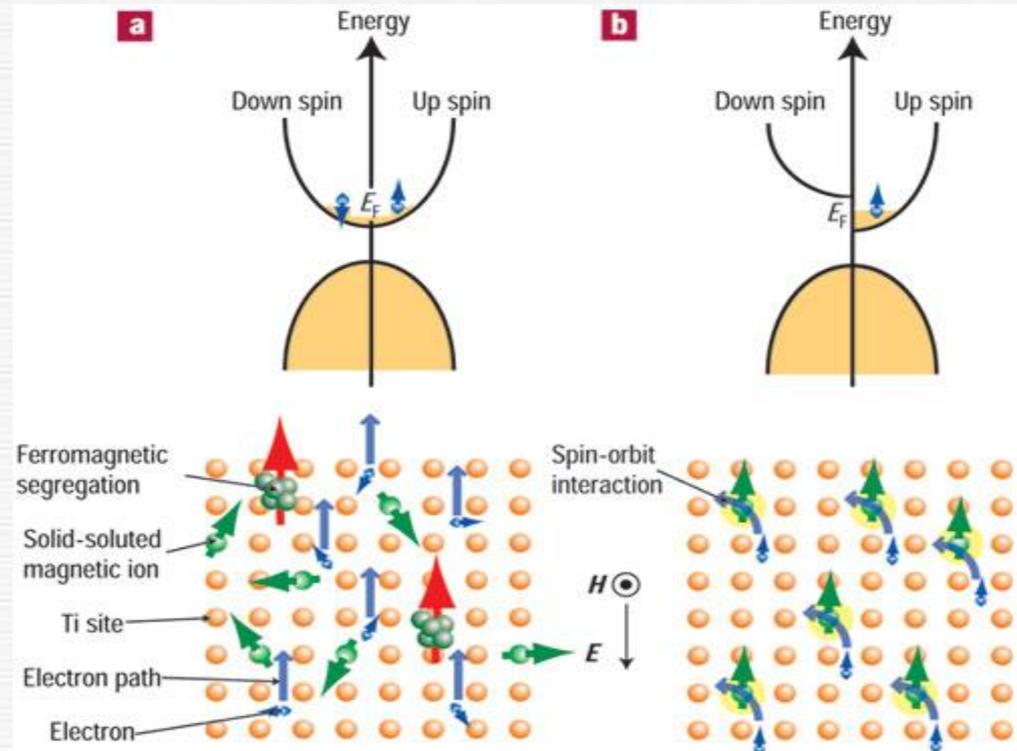
Spin Hall Effect

- Separation of electron spins in current-carrying object, no magnetic field needed
- Predicted in 1971, observed in 2004 via emission of circularly polarized light
- Universal, present in **metals and semiconductors at high and low temperature**

Anamolous Hall Effect

- Ferromagnetic materials have internal magnetic field

Via Toyosaki et al.
2004



- Much larger than normal Hall Effect, but not well understood ; Possible Berry-phase effect

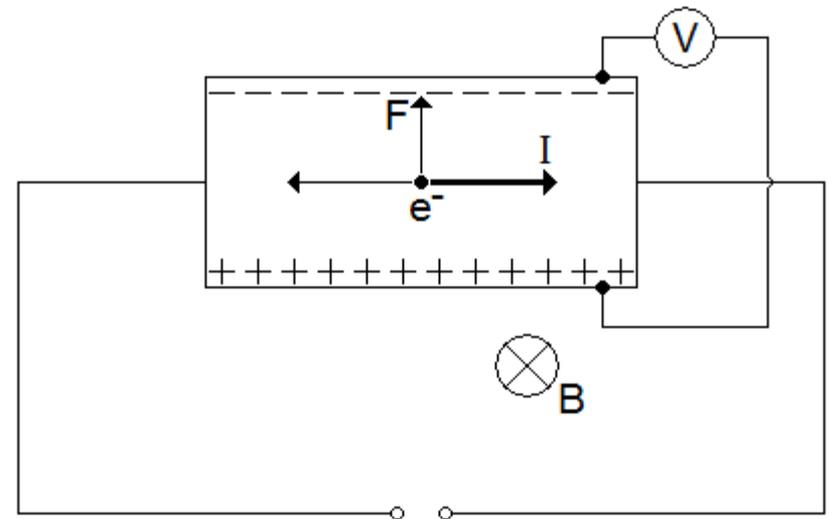


Hall Effect Measurements

This transverse voltage is the Hall voltage V_H and its magnitude is equal to IB/qnd , where I is the current, B is the magnetic field, d is the sample thickness, and q (1.602×10^{-19} C) is the elementary charge.

In some cases, it is convenient to use **layer or sheet density ($n_s = nd$)** instead of bulk density. One then obtains the equation:

$$n_s = \frac{IB}{q|V_H|}$$





Hall Effect Measurements

Thus, by measuring the Hall voltage V_H and from the known values of I , B , and q , one can determine the sheet density n_s of charge carriers in semiconductors. If the measurement apparatus is set up as shown, the Hall voltage is **negative for n -type semiconductors and positive for p -type semiconductors**. The sheet resistance R_s of the semiconductor can be conveniently determined by use of the Van der Paw resistivity measurement technique. Since **sheet resistance involves both sheet density and mobility**, one can determine the Hall mobility from the equation

$$\mu = \frac{|V_H|}{R_s I B} = \frac{1}{q n_s R_s}$$

If the conducting layer thickness d is known, one can determine the bulk resistivity ($r = R_s d$) and the bulk density ($n = n_s / d$).



The Van der Pauw Technique

Van der Pauw equation:

$$e^{-\frac{\pi R_A}{R_s}} + e^{-\frac{\pi R_B}{R_s}} = 1$$

In which $R_A = \frac{V_{43}}{I_{12}}$ $R_B = \frac{V_{14}}{I_{23}}$

The bulk electrical resistivity ρ can be calculated

$$\rho = R_s d$$

Hall measurement in the Van der Pauw technique is to determine the sheet carrier density n_s by measuring the Hall voltage V_H

To measure the Hall voltage V_H ,

current I contacts 1 and 3

the Hall voltage $V_H (=V_{24})$ contacts 2 and 4.

the sheet carrier density n_s can be calculated

$$n_s = \frac{IB}{q|V_H|}$$

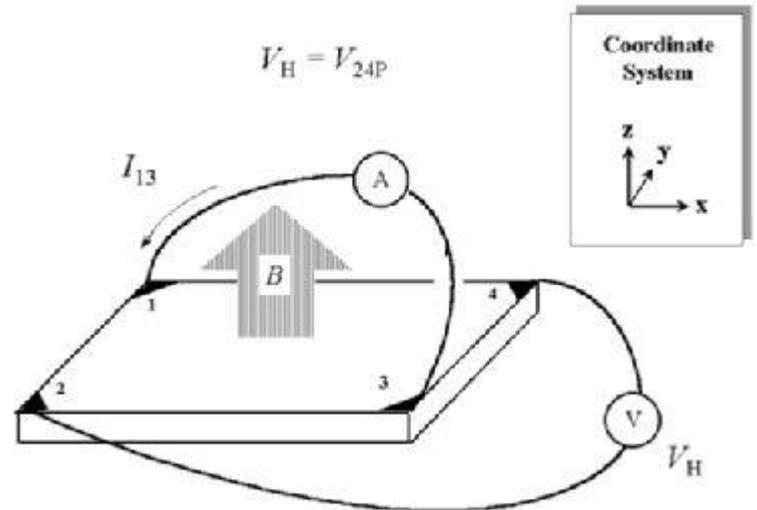
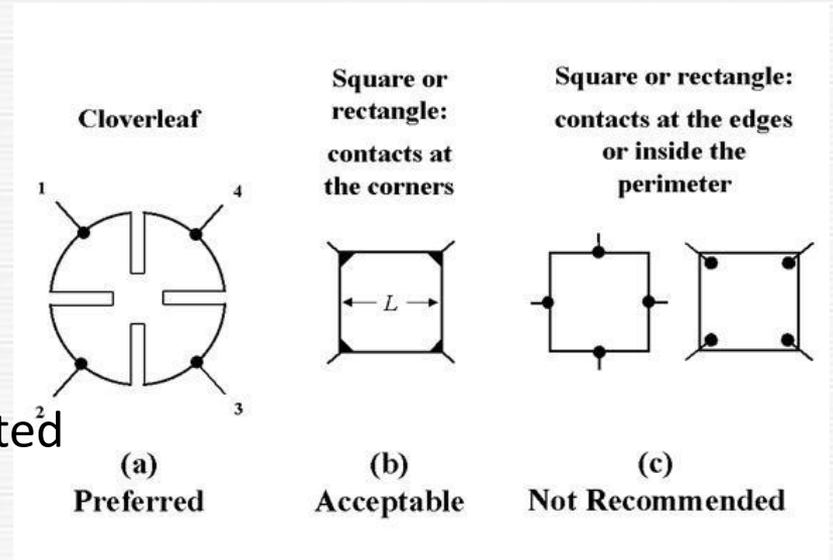


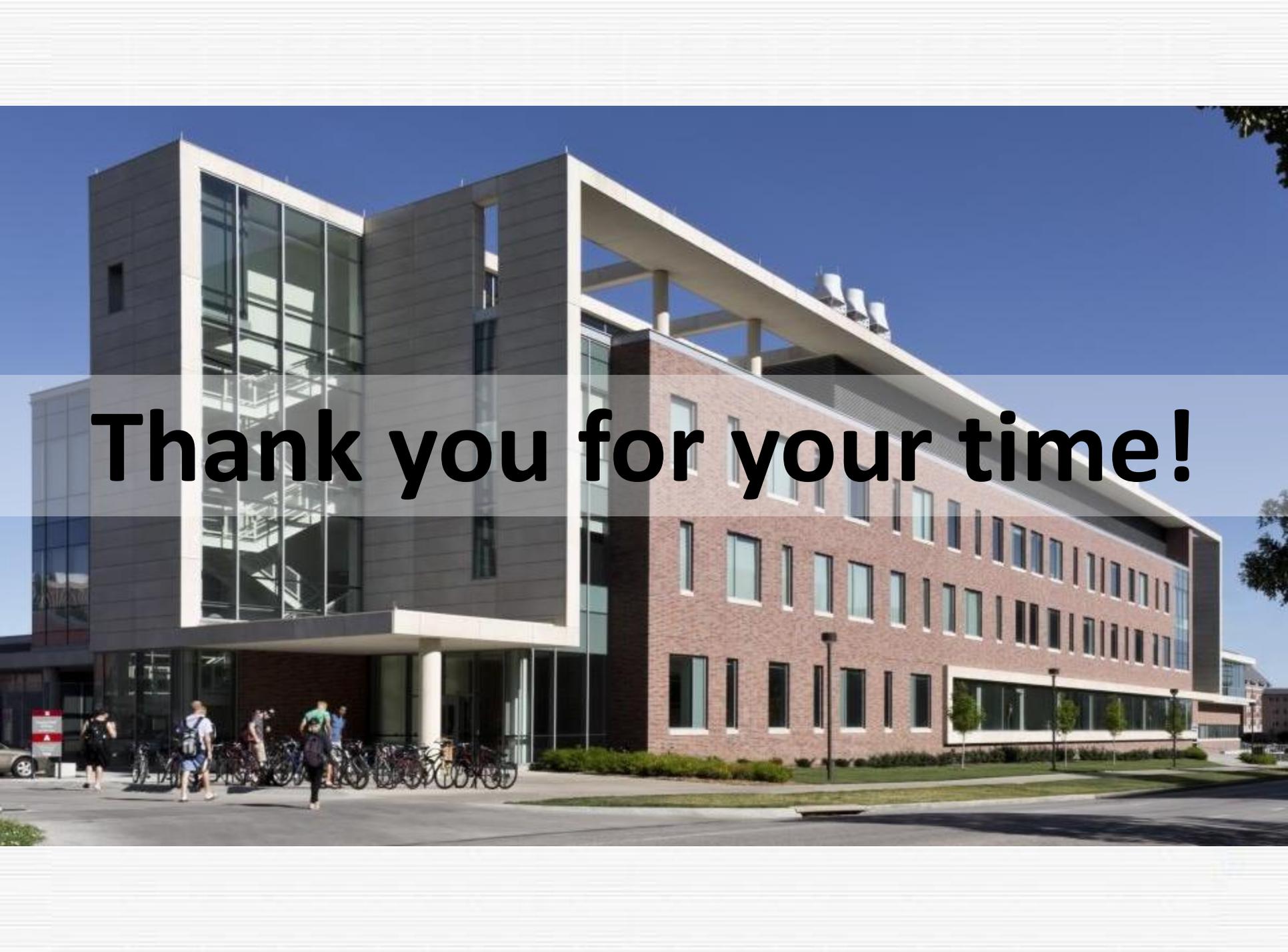
Figure 3



Summary

- Hall effect and the new phenomena
- ✓ Quantum Hall Effect
- ✓ Spin Hall Effect
- ✓ Anomalous Hall Effect
- Simple measurement of Hall effect

Next topic: Hall bar, normal Hall effect and Anomalous Hall Effect

A photograph of a modern university building. The building features a prominent glass facade on the left side, showing an interior staircase, and a brick facade on the right side. The building has a unique architectural design with a large, open rectangular frame structure. In the foreground, several people are walking, and a large number of bicycles are parked in a designated area. The sky is clear and blue.

Thank you for your time!



Density of Charge Carriers

Calculation of the density of free electrons in a metal like copper involves the basic physical data about the metal, plus the fact that copper provides about one free electron per atom to the electrical conduction process. A representative value can be calculated with the following data.

Molar mass of copper = $63.54 \text{ gm} / \text{mol} = 63.54 \times 10^{-3} \text{ kg} / \text{mol} = M$

Density of copper = $9 \text{ gm} / \text{cm}^3 = 9 \times 10^3 \text{ kg} / \text{m}^3 = \rho$

Number of free electrons per mol = Avogadro's number = $6.02 \times 10^{23} / \text{mol} = N_A$

Number of free electrons per unit volume = n

$$n = \frac{\text{mass} / \text{m}^3 \times \text{atoms} / \text{mol}}{\text{mass} / \text{mol}} = \text{atoms} / \text{m}^3$$

$$n = \frac{\rho N_A}{M} = 8.5 \times 10^{28} \text{ electrons} / \text{m}^3$$

This is a nominal value because the density of copper in electrical wiring cables varies somewhat with processing.